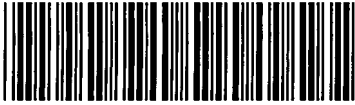


**Search Notes**

Application/Control No.

10/760,590

Examiner

Randall Chin

Applicant(s)/Patent under  
Reexamination

BOYER ET AL.

Art Unit

1744

**SEARCHED**

Class	Subclass	Date	Examiner
15	116.2	↓	↓
15	119.2	7/5/2007	RC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST, OCR, EPO, DERWENT, JPO	↓	↓
Inventor name search	7/5/2007	RC